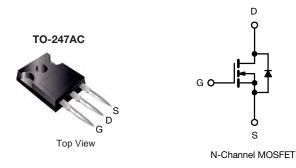


## IXFH23N60Q-VB Datasheet

# N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V) at T <sub>J</sub> max.	650				
R <sub>DS(on)</sub> (Ω) at 25 °C	$V_{GS} = 10 V$	0.19			
Q <sub>g</sub> max. (nC)	106				
Q <sub>gs</sub> (nC)	14				
Q <sub>gd</sub> (nC)	33				
Configuration	Single				



### **FEATURES**

- Reduced t<sub>rr</sub>, Q<sub>rr</sub>, and I<sub>RRM</sub>
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q<sub>rr</sub>
- Ultra low gate charge (Q<sub>q</sub>)

Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Telecommunications
  - Server and telecom power supplies
- Lighting
  - High-intensity discharge (HID)
- Fluorescent ballast lighting
- Consumer and computing - ATX power supplies
- Industrial
  - Welding
  - Battery chargers
- Renewable energy
- Solar (PV inverters)
- Switch mode power supplies (SMPS)

ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> :	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	650	V	
Gate-Source Voltage			V <sub>GS</sub>	± 30		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	- I <sub>D</sub> -	20		
		T <sub>C</sub> = 100 °C		13	А	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	53		
Linear Derating Factor				1.7	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	367	mJ	
Maximum Power Dissipation			PD	208	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		d\//dt	37		
Reverse Diode dV/dt <sup>d</sup>		dV/dt	31	V/ns		
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s			300	°C	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD} = 50$  V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 5.1 A.

c. 1.6 mm from case.

d.  $I_{SD} \leq I_D$ , dl/dt = 100 A/µs, starting  $T_J$  = 25 °C.



THERMAL RESISTANCE RAT	INGS							
PARAMETER	SYMBOL	TYP.		MAX.		UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-		62				
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-				°C/W		
	•	•						
<b>SPECIFICATIONS</b> ( $T_J = 25 \ ^{\circ}C$ , u	unless otherw	ise noted)						
PARAMETER	SYMBOL		T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static								L
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> =	250 µA	650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			I <sub>D</sub> = 1 mA	-	0.67	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>		= V <sub>GS</sub> , I <sub>D</sub> =		2	-	4	V
		-	$V_{GS} = \pm 20 V$		-	-	± 100	nA
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 30 \text{ V}$		-	-	± 1	μA	
Zero Gate Voltage Drain Current			= 520 V, V <sub>0</sub>		-	-	1	
	I <sub>DSS</sub>			V, T <sub>J</sub> = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V		<sub>D</sub> = 11 A	-	0.19	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub>	= 30 V, I <sub>D</sub>	= 11 A	-	7.0	-	S
Dynamic	•	•			•	•	•	
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 \	1	-	2322	-	
Output Capacitance	C <sub>oss</sub>		V <sub>DS</sub> = 100 V, f = 1 MHz		-	105	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>				-	4	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>				-	84	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>	$V_{DS} = 0 V$ to 520 V, $V_{GS} = 0 V$		-	293	-		
Total Gate Charge	Qg				-	71	106	1
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V I <sub>D</sub> = 11 A, V <sub>DS</sub> = 520 V		-	14	-	nC	
Gate-Drain Charge	Q <sub>gd</sub>				-	33	-	1
Turn-On Delay Time	t <sub>d(on)</sub>		$V_{DD}$ = 520 V, $I_{D}$ = 11 A, $V_{GS}$ = 10 V, $R_{g}$ = 9.1 $\Omega$		-	22	44	- ns
Rise Time	t <sub>r</sub>	V <sub>DD</sub> =			-	34	68	
Turn-Off Delay Time	t <sub>d(off)</sub>	V <sub>GS</sub> :			-	68	102	
Fall Time	t <sub>f</sub>			-	42	84	]	
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	0.78	-	Ω	
Drain-Source Body Diode Characteristi	cs							
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	21	A	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	53		
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 11 A, V <sub>GS</sub> = 0 V		-	0.9	1.2	V	
Reverse Recovery Time	t <sub>rr</sub>		T <sub>.1</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 11 A,		-	160	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 2$			-	1.2	-	μC
Reverse Recovery Current	I <sub>RRM</sub>	dľ/dt = 100 Å/µs, $V_R$ = 25 V		-	14	-	A	

#### Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

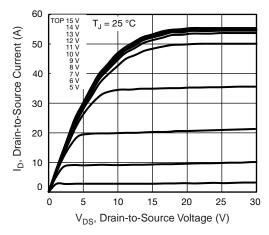


Fig. 1 - Typical Output Characteristics



Fig. 2 - Typical Output Characteristics

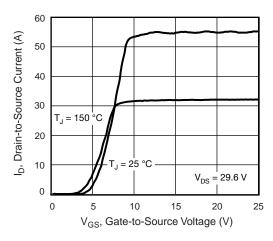


Fig. 3 - Typical Transfer Characteristics

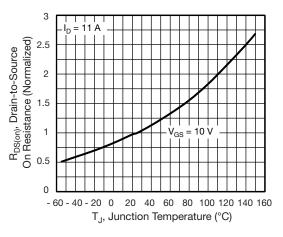


Fig. 4 - Normalized On-Resistance vs. Temperature

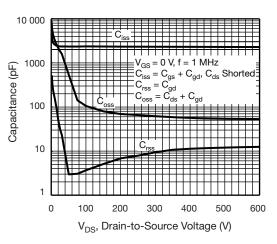


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



Fig. 6 -  $C_{oss}$  and  $E_{oss}$  vs.  $V_{DS}$ 

## IXFH23N60Q-VB



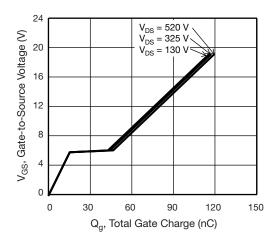


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

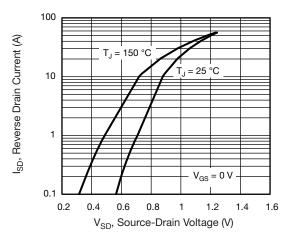


Fig. 8 - Typical Source-Drain Diode Forward Voltage

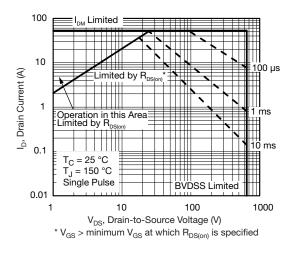


Fig. 9 - Maximum Safe Operating Area

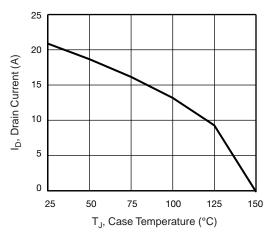


Fig. 10 - Maximum Drain Current vs. Case Temperature



Fig. 11 - Temperature vs. Drain-to-Source Voltage





Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case



Fig. 13 - Switching Time Test Circuit



Fig. 14 - Switching Time Waveforms



Fig. 15 - Unclamped Inductive Test Circuit

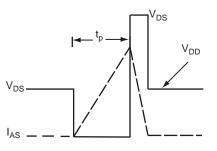


Fig. 16 - Unclamped Inductive Waveforms

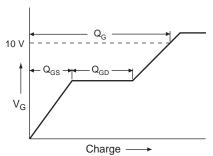
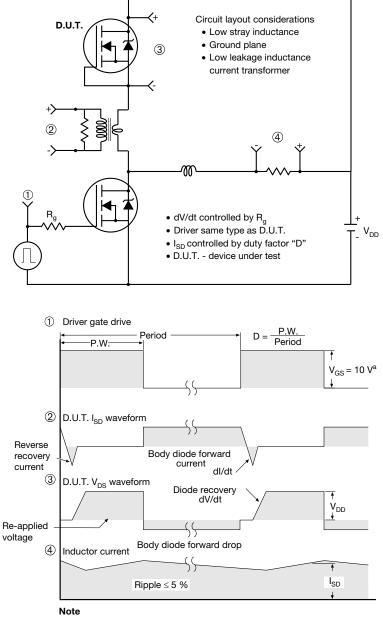


Fig. 17 - Basic Gate Charge Waveform





## Peak Diode Recovery dV/dt Test Circuit



a.  $V_{GS} = 5$  V for logic level devices

Fig. 19 - For N-Channel



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